BT1306-400D/600D



Logic level triac

Rev. 2 — 14 September 2011

Product data sheet

1. **Product profile**

1.1 General description

Logic level sensitive gate triac intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

1.2 Features and benefits

- Sensitive gate in all four quadrants
- Low cost package.

1.3 Applications

- General purpose bidirectional switching
- Solid state relays

- Phase control applications
- Low power AC fan speed controllers.

1.4 Quick reference data

- $V_{DRM} \le 600 \text{ V (BT1306-600D)}$
- $I_{TSM} \le 8 A$

- V_{DRM} ≤ 400 V (BT1306-400D)
- $I_{T(RMS)} \le 0.6 A$.

Pinning information 2.

Table 1. Pinning - SOT54 (TO-92), simplified outline and symbol

Pin	Description	Simplified outline	Symbol			
1	main terminal 2	4	4			
2	gate	2,	1			
3	main terminal 1		msb033	2 mb/305		
	SOT54 (TO-92)					



3. Ordering information

Table 2. Ordering information

Type number	Package	Package			
	Name	Description	Version		
BT1306-600D	TO-92	Plastic single-ended leaded (through hole) package; 3 leads	SOT54		
BT1306-400D	TO-92	Plastic single-ended leaded (through hole) package; 3 leads	SOT54		

4. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage				
	BT1306-600D	$25 ^{\circ}\text{C} \le T_j \le 125 ^{\circ}\text{C}$		600	V
	BT1306-400D		-	400	V
I _{T(RMS)}	on-state current (RMS value)	full sine wave; $T_{lead} \le 65$ °C; Figure 1 and 2	-	0.6	Α
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_j = 25$ °C prior to surge; Figure 3 and 4			
		t = 20 ms	-	8	Α
		t = 16.7 ms	-	8.8	Α
I ² t	I ² t for fusing	t = 10 ms	-	0.32	A ² s
dI _T /dt	repetitive rate of rise of on-state current after triggering	$I_{TM} = 1 \text{ A}; I_G = 0.2 \text{ A}; dI_G/dt = 0.2 \text{ A/}\mu\text{s}$			
		T2+ G+	-	50	A/μs
		T2+ G-	-	50	A/μs
		T2- G-	-	50	A/μs
		T2- G+	-	10	A/μs
I_{GM}	gate current (peak value)	t = 2 μs max	-	1	Α
V_{GM}	gate voltage (peak value)		-	5	V
P_{GM}	gate power (peak value)		-	5	W
$P_{G(AV)}$	average gate power	t = 2 μs max; $T_{case} \le 80$ °C	-	0.1	W
T _{stg}	storage temperature		-40	+150	°C
T _j	junction temperature		-40	+125	°C

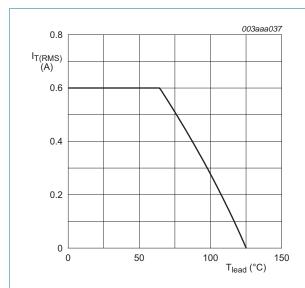
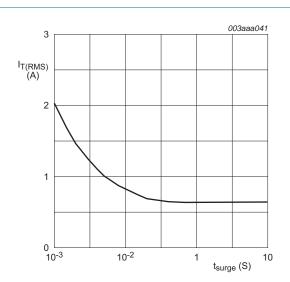
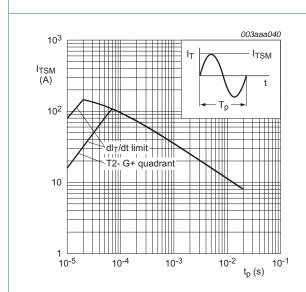


Fig 1. Maximum permissible on-state current (RMS value) as a function of lead temperature.



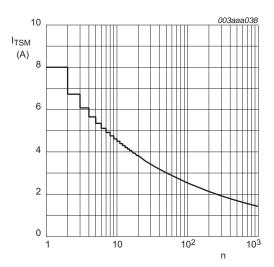
f = 50 Hz $T_{lead} \le 65 \,^{\circ}\text{C}$

Fig 2. Maximum permissible repetitive on-state current (RMS value) as a function of surge duration for sinusoidal currents.



 $t_p \le 20 \text{ ms}$ initial $T_j \le 25 \, ^{\circ}\text{C}$

Fig 3. Maximum permissible non-repetitive peak on-state current as a function of pulse width for sinusoidal currents.



n = number of cycles

f = 50 Hz

initial $T_j \le 25$ °C

Fig 4. Maximum permissible non-repetitive peak on-state current as a function of number of cycles for sinusoidal currents; typical values.

5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-lead)}$	thermal resistance from junction to lead	full cycle	-	-	60	K/W
		half cycle			80	
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed-circuit board; lead length = 4 mm; <u>Figure 5</u>	-	150	-	K/W

5.1 Transient thermal impedance

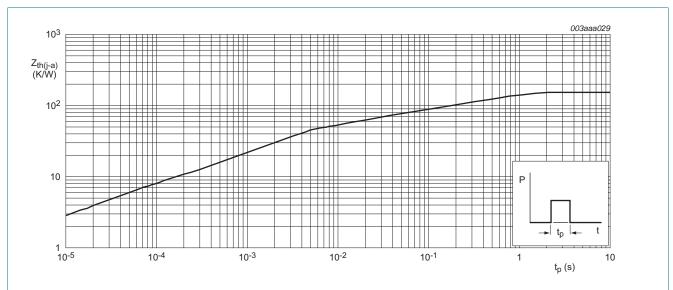


Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values.

6. Characteristics

Table 5. Characteristics

 $T_j = 25$ °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
Static cha	racteristics						
I _{GT} ga	gate trigger current	V _D = 12 V; I _T = 0.1 A; <u>Figure 8</u>					
		T2+ G+	-	1	5	mΑ	
		T2+ G-	-	2	5	mΑ	
		T2- G-	-	2	5	mΑ	
		T2- G+	-	4	7	mΑ	
IL	latching current	V _D = 12 V; I _T = 0.1 A; <u>Figure 9</u>					
		T2+ G+	-	1	10	mΑ	
		T2+ G-	-	5	10	mΑ	
		T2- G-	-	1	10	mΑ	
		T2- G+	-	2	10	mΑ	
I _H	holding current	V _D = 12 V; I _{GT} = 0.1 A; <u>Figure 10</u>	-	1	10	mΑ	
V _T	on-state voltage	I _T = 0.85 A; <u>Figure 11</u>	-	1.4	1.9	V	
V_{GT}	gate trigger voltage	V _D = 12 V; I _T = 0.1 A; <u>Figure 7</u>	-	0.9	2	V	
		$V_D = V_{DRM}; I_T = 0.1 A; T_j = 110 ^{\circ}C$	0.1	0.7	-	V	
I _D	off-state leakage current	$V_D = V_{DRM(max)}$; $T_j = 110 ^{\circ}C$	-	3	100	μΑ	
Dynamic	characteristics						
dV _D /dt	critical rate of rise of off-state voltage	$V_D = 67\%$ of $V_{DM(max)}$; $T_{case} = 110$ °C; exponential waveform; gate open circuit; Figure 12	30	45	-	V/µs	
dV _{com} /dt	critical rate of rise of commutation voltage	V_D = rated V_{DM} ; T_{case} = 50 °C; I_{TM} = 0.84 A; commutating dl/dt = 0.3 A/ms	-	5	-	V/µ	
t _{gt}	gate controlled turn-on time	$I_{TM} = 1.0 \text{ A}; V_D = V_{DRM(max)}; I_G = 25 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}$	-	2	-	μS	

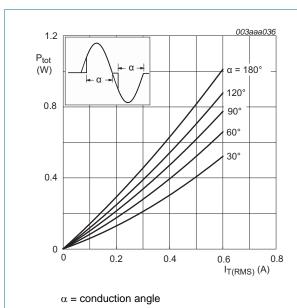


Fig 6. On-state dissipation as a function of on-state current (RMS value); maximum values.

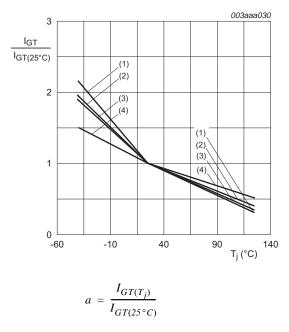
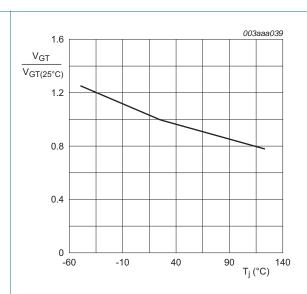
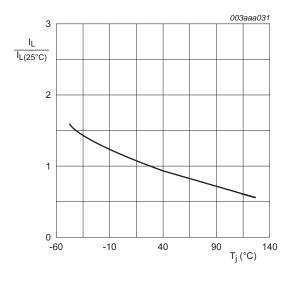


Fig 8. Normalized gate trigger current as a function of junction temperature; typical values.



$$a = \frac{V_{GT(T_j)}}{V_{GT(25°C)}}$$

Fig 7. Normalized gate trigger voltage as a function of junction temperature; typical values.



 $a = \frac{I_{L(T_j)}}{I_{L(25^{\circ}C)}}$

Fig 9. Normalized latching current as a function of junction temperature; typical values.

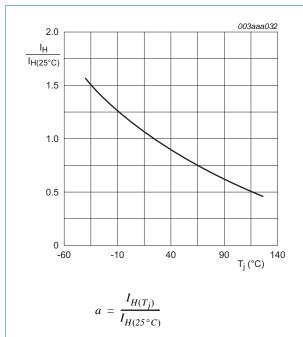


Fig 10. Normalized holding current as a function of junction temperature; typical values.

Fig 11. On-state current as a function of on-state voltage; typical and maximum values.

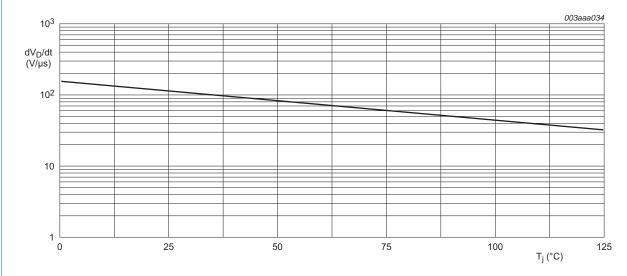
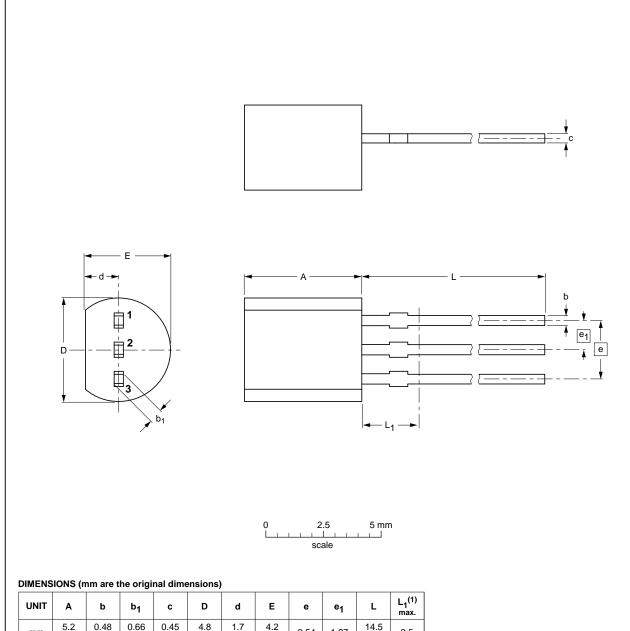


Fig 12. Critical rate of rise of off-state voltage as a function of junction temperature; typical values.

Package outline

Plastic single-ended leaded (through hole) package; 3 leads

SOT54



UNIT	A	b	b ₁	С	D	d	E	е	e ₁	L	L ₁ ⁽¹⁾ max.
mm	5.2 5.0	0.48 0.40	0.66 0.55	0.45 0.38	4.8 4.4	1.7 1.4	4.2 3.6	2.54	1.27	14.5 12.7	2.5

1. Terminal dimensions within this zone are uncontrolled to allow for flow of plastic and terminal irregularities.

OUTLINE		REFERENCES				ISSUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT54		TO-92	SC-43A			04-06-28 04-11-16

Fig 13. SOT54 (TO-92).

BT1306_XXXD_SER

8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BT1306_XXXD_SER v.2	20110914	Product data sheet	-	BT1306_XXXD_SER v.1 (9397 750 12593)
Modifications:		of this data sheet has beer f NXP Semiconductors.	n redesigned to comply w	rith the new identity
	 Legal texts l 	nave been adapted to the	new company name whe	re appropriate.
	 Package ou 	tline drawings have been u	updated to the latest vers	sion.
BT1306_XXXD_SER v.1 (9397 750 12593)	20040219	Product data	-	-

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9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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